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Synchrotron scanning transmission x-ray spectro-microscopy (STXM) characterisation of β -SiC nanowhisker AZ91 magnesium alloy nanocomposites

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ABSTRACT

β-SiC nanoparticles are one of the most common reinforcements in Mg-Al alloy matrix nanocomposites (MgMNCs). The interfacial interactions between β-SiC and the alloy matrix are complex due to the occurrence of new phases and the fine scale of the 3D architecture. This study aims to explore the feasibility of using synchrotron Scanning Transmission X-ray spectro-Microscopy (STXM) to investigate such interfacial interactions and acquire reference X-ray Absorption Spectroscopy (XAS) data for some common interphase crystals present within the composites, which are not readily available. Throughout this study, a reliable procedure for collecting STXM data on samples derived from MgMNCs was developed, and reference XAS spectra for α-Mg, β-Mg₁₇Al₁₂, T2-Al₂MgC₂, Mg₂Si and MgO present in MgMNCs were collected. The accessibility of STXM and spatially resolved XAS spectrum is not only useful for nanocomposite alloy research but applicable widely across the magnesium alloy research community when identifying and quantifying the phases with complex crystal structures and oxide states.

1. Introduction

Mg matrix nanocomposites (MgMNCs) are promising lightweight structural materials for the automotive and aeronautics industries given their high strength at intrinsically low densities [1,2]. Among these nanocomposites, AZ series alloy matrices (Mg alloyed with Al and Zn) reinforced by SiC nanoparticles (NPs) are some of the most frequently researched [3,4], motivated by wide material availability, excellent mechanical performance and good wettability during the melt manufacturing process [3,4].

This good interfacial compatibility between SiC and Mg-Al alloys has been attributed to the good lattice match between β -SiC and α -Mg phase [5–8] as well as specific interfacial reactions between β -SiC and Mg-Al alloy melt [9–11]. During the interfacial reactions, a variety of binary or ternary carbides containing Mg and Al may occur; some typical examples include Al₄C₃ [12], MgC [13], AlC₂ [14] and Al₂MgC₂ [15–17]. Despite numerous studies detailing the compositions and crystallographic information of these carbides, their formation mechanisms and orientations relationships with the α -Mg phase have not been fully characterised [18–21]. This lack of comprehensive understanding is likely attributed to the challenges associated with sample preparation, particularly due to the easily hydrolysable nature of these carbides [17]. A deeper comprehension of these interphase crystals sheds light on their impact on the microstructure of MgMNCs. This includes effects such as nanofiller dispersion and associated grain refinement, along with the corrosion resistance of the composites, which collectively define the performance of the composite materials.

Scanning transmission X-ray spectro-microscopy (STXM) at PSI,

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Fig. 1. (a) Image of the AZ91D machinery chips used in our study. (b) SEM image of the as-received β -SiC_{nw} used in this study. (c) Sketch of the ingots obtained after gravity casting.

Switzerland, provides new opportunities to characterise these interphase crystals within a sample with micron-scale thickness. STXM provides direct transmission images of the sample microstructure (with spatial resolution around tens of nanometres [22,23]) together with a spatially resolved X-ray absorption spectroscopy (XAS) spectrum (with energy resolution around 0.5 eV) [24-26]; the resulting spectral imaging provides both morphology and some crystallographic information, in principle allowing the atomic coordinates, electronic structure and crystal symmetry of the interfacial products to be determined. To analyse the XAS spectrum of an unknown phase, the most common approach is to compare its spectral feature with a library of reference compounds. However, to our knowledge, the spectra of some common phases in the β -SiC reinforced Mg-Al matrix nanocomposite are not readily available in literature. Hence, in this work, we aimed to capture reference XAS spectra on phases identified at β-SiC nanowhiskers (SiC_{nw}) - AZ91 interface, confirmed by high resolution electron microscopy.

2. Experimental

The β-SiC_{nw} reinforced AZ91 matrix nanocomposite was manufactured by melt stirring and gravity casting as in our previous publication [2]. 140 g of AZ91D machinery chips (Fig. 1(a) and the detailed elemental composition in Table 1, provided by non ferrum GmbH, Austria) were first melted in a boron nitride coated steel crucible at 650 °C under Ar gas protection. After ensuring the chips were melted completely, 1 vol% $\beta\text{-SiC}_{nw}$ powder was then added to the melt, wrapped in an Al foil packet. The $\beta\mbox{-SiC}_{nw}$ used in this study was provided by Haydale Ltd (USA) with average diameter and length of 0.44 \pm 0.10 μm and 5.48 \pm 0.17 μm , respectively (confirmed with multiple SEM images; example shown in Fig. 1(b)). The mixture was subsequently stirred at 390 RPM for 2 hours before casting into a steel mould pre-heated at 200 °C. In the last 5 min of stirring, the melt temperature was increased to 680 °C to improve fluidity during casting. The cast ingot consisted of four cylindrical rods with each rod of 1 cm in diameter and 14 cm in height (Fig. 1(c)). For comparison, reference samples made from pure AZ91 alloy were also prepared following the same casting process.

Finally, to obtain the XAS spectrum of MgO formed during the stir-casting process, a pure AZ91 sample was also prepared without adequate Ar protection during stir-casting at 650°C.

To analyse the interphase crystals between SiC_{nw} and AZ91 matrix, cross-sections from different parts of the casted ingots were cut, ground and polished based on the standard metallographic sample preparation steps for AZ91 alloys [18]. To avoid oxidation of Mg matrix and hydrolysis of any carbide phases, water was strictly avoided during the grinding and polishing process. Before Scanning electron microscopy (SEM), all the cross-sections were subjected to Ar ion polishing at 4 kV voltage and 1° gun tilt for 8 hours to eliminate any hydrolysed carbides and oxides formed during sample transportation and protruding SiC_{nw} on the cross-sections (formed during grinding and polishing due to the soft Mg alloy matrix).

The microstructural analysis was conducted using a Zeiss Sigma-300 SEM (Zeiss, Germany). Initially, the phase distributions were examined in backscattered (BSD) electron mode, utilising an acceleration voltage of 20 keV and working distance of 15 mm. Subsequently, the phases of interests were further investigated in secondary (SE) electron mode with an acceleration voltage of 5 keV and working distance of 5 mm.

To further identify the phases of interest within MgMNC and establish reference areas for XAS spectra analysis, energy dispersive X-ray (EDX) spectroscopy (Bruker, Germany) was performed using SE-SE setup. For the carbide phases formed at SiC_{nw} – AZ91 interface, Electron Backscatter Diffraction (EBSD) and Scanning Transmission Electron Microscopy (STEM) were employed to analyse their crystal structure, interfaces, and local chemistry.

In this study, the EBSD analysis was performed using Bruker eFlash detector (Bruker, Germany) equipped in Zeiss Sigma-300 SEM with the SEM-BSD setup and 70° sample tilt. STEM examination was carried out using the High-Angle Annular Dark Field (HAADF) detector equipped in the Themis-Z double corrected analytical STEM (ThermoFisher, USA), operating at 300 keV. The sample for STEM was prepared using strata (ThermoFisher, USA) Focus Ion Beam (FIB), following the standard lift-out procedure for TEM sample preparation.

The STXM measurement was carried out in the Pollux beamline at PSI [25,26]. During the measurement, a 25 nm zone plate was used to focus the monochromatised soft X-ray beam onto a sample and the transmitted beam intensity was recorded as a function of sample position and photon energy in order to produce X-ray images or XAS spectra. The lamella samples for STXM were prepared by FIB Helios (Thermo-Fisher, USA) with standard lift-out procedure for TEM sample except that the lamella for STXM were thicker. The samples were kept at 12 µm in width and 5 µm in height so that the phases of interest, as pre-determined by SEM, were included. The thickness of the lamella was determined by the thickness of the phases of interest, therefore it was kept less than 2.5 µm to avoid overlapped spectra (caused by other phases near the interface) and match the soft X-ray attenuation length in Mg [24]. Besides, the potential influence of ion beam damage during FIB and X-ray radiation damages during STXM scanning on XAS spectrum was believed to be negligible considering much larger sample thickness in comparison to the ion beam damage layer [27] and good phases stabilities within Mg-Al alloys under ionising radiation [28].

During STXM scanning, regions of interest (ROIs) were first identified by single-energy images across the whole lamella area. Then, the ROIs were subsequently examined by X-ray spectral maps across the energy ranges of the Mg and Al K-edges. Table S1 in the supplementary document summarised the specific STXM experimental parameters used in this study including scanned energy range, scanning step size and energy step size. These values were determined based on the energy

Table 1

| Elemental composition of AZ9 | 1 alloys in weight percent | provided by non-ferrum | GmbH |
|------------------------------|----------------------------|------------------------|------|
|------------------------------|----------------------------|------------------------|------|

| Mg | Al | Zn | Mn | Si | Cu | Ni | Fe | Be | others |
|---------|-------------|-------------|---------------|---------------|---------------|---------------|---------------|---------------|---------------|
| Balance | 8.500–9.500 | 0.450–0.900 | 0.170 - 0.400 | 0.000 - 0.080 | 0.000 - 0.025 | 0.000 - 0.001 | 0.000 - 0.004 | 0.000 - 0.001 | 0.000 - 0.010 |



(caption on next page)

Fig. 2. (a) SEM-secondary electron (SEM-SE) image of the sample used for capturing reference XAS spectrum for β-phase (outlined by red dotted line) and α-Mg (remainder). (b) SEM-SE image of the cross-section before lifting out during FIB preparation. The insets of these two images are the collected by EDX point analysis. (c) STXM image captured near Mg K-edge at 1315 eV. (d) STXM image captured near Al K-edge at 1587 eV. The scalebars in images (a), (b), (c) and (d) are 2 µm. The red line in panel (c) and (d) and the green line in (c) indicate the position of the line scan used for capturing XAS of β-phase and α-Mg phase. (e) The XAS spectrum for β-phase near Mg K-edge. (f) The XAS spectrum for β-phase near Al K-edge. (g) The XAS spectrum for α-Mg near Mg K-edge captured in this study (green line) and replotted from Richardson et al. [37] (black line).

range of Mg and Al K-edge and theoretical energy (around 1.5 eV) and spatial resolution (around 100 nm) of the STXM at PolLux beamline. Depending on the dimensions of ROIs and the necessity of acquiring its STXM images, the scanning mode can be either along a line ('line scan' for features with a relatively large dimension and/or when microstructural information is not necessary) or across a 2D section ('stack scan' for features with a relatively small dimension and/or when microstructural information is important).

Following STXM scanning, aXis2000 software [29] was used to process the XAS spectra and images acquired during the experiment. During the XAS spectrum extraction, the optical density (OD) of the spectra was obtained by normalising the transmitted X-ray intensity with respect to the incidence intensity (measured via an empty sample region). The energies of all the XAS spectra were calibrated by using standard MgO spectrum [30–32]. Further analysis such as image stacking, spectra comparison and linear combination fitting were performed in ImageJ, MATLAB 2023 and Larch software [33], respectively.

3. Results and discussion

In order to capture the XAS spectra of the β -phase, α -Mg, T2-Al₂MgC₂ carbide, Mg₂Si and MgO phases, SEM and EDX point analysis were first carried out to locate suitable regions for the STXM sample, and to confirm the local composition (Figs. 2–5). For the carbide phase identified at β -SiC_{nw} – AZ91 interface, additional EBSD and TEM analysis were carried out to confirm their crystal structures (Fig. 3(c) to (f)) due to the possibility of forming different polymorph. Based on the indexed Selected Area Electron Diffraction (SAED) pattern showed in Fig. 3(f), the carbide phase formed was identified as T2-Al₂MgC₂ with the calculated lattice parameters of a = 3.4075 Å and c = 5.8120 Å. These values were closed to the theoretical lattice parameters of this crystal determined by X-ray powder diffraction with a = 3.3770 Å and c = 5.8171 Å [34.35].

To avoid the possible influence of the SiC_{nw} addition, the lamellae containing β -phase and α -Mg were selected from the polished crosssection obtained from the pure AZ91 sample (Fig. 2(a) & (b)). During the STXM experiment, 'line scans' at the positions indicated in Fig. 2(c) & (d) were carried out to acquire the XAS spectra of these two phases. For samples containing MgO, Mg₂Si and T2-Al₂MgC₂ phases, 'stack scans' were carried out to capture their STXM images at different energy steps and compensate the influence of sample drifting. In the post-analysis of the 'stack scan', the scanning data was initially aligned based on the STXM images at different energy steps. Subsequently, regions of interest (corresponding to the positions of the phases) for generating XAS spectra were determined from the STXM images (Fig. 3 (g) & (h), Fig. 4(c) and Fig. 5(c)) based on the contrast formed via X-ray absorption and by aligning with the SEM image of the lamella sample collected after FIB cutting.

The XAS spectra of all the phases collected in this study were plotted together in Fig. 6(a) & (b). By considering the energy shift related to the rising edge, regions within these spectra can be categorised as X-ray absorption near-edge structure (XANES) or extended X-ray absorption fine structure (EXAFS) [36]. In this study, we designated the region before first destructive interference observed (around 1333 eV in Mg K-edge and around 1592 eV in Al K-edge) within the spectrum as XANES and the region afterwards as EXAFS. Tables 2 and 3 summarised the energy positions of some features observed at XANES of the phases collected in this study. After comparing the relative energy positions of

these features, with respect to the rising edge, similar energy positions were noted for the features identified between α -Mg and β -phase as well as between MgO and Mg₂Si. This observation could be attributed to the similar Mg oxide states within these two pairs of phases. Additionally, by comparing the features at EXAFS, the spectrum of MgO exhibited distinct constructive and destructive energy positions compared to the spectra of the other phases (Fig. 6(a)). By considering the formation mechanism of MgO during Mg melt oxidation, this difference might be explained the small particle size (100 nm) and powder nature of the MgO [37].

To confirm the reliability of the measurements, where available, reference XAS spectrum available from previous research were replotted for comparison. From the comparison for the XAS spectrum for α -Mg (Fig. 2(g)) [38] and MgO (Fig. 5(d)) [24,30], similar spectral shapes and relative peak positions (Table 2) were identified which confirms the reliability of the current procedures to capture reference NEXAFS spectrum.

To illustrate the applicability of these reference spectra in STXM analysis, the new XAS spectra were used to probe additional unidentified phases within the lamella presented in Fig. 3. The locations of these phases were identified based on their contrast in STXM images captured near the Mg K-edge and Al K-edge (Fig. 7(a&b)), which was due to their varying X-ray absorption. By direct comparisons and linear combination fittings of these extracted XAS spectra with the reference spectra presented in Fig. 6 (Figure S1 and Table S2), the predominantly interphase crystals at ROI 1-3 were identified as: T2-Al₂MgC₂, α-Mg, and a combination of T2-Al₂MgC₂ and α -Mg, respectively. This result highlights the utility of the reference spectra collected in this work for compositional analysis after STXM spectral imaging. Coupling the compositional information with the morphological details provided by STXM images can provide insights into interphase crystals, both their 3D morphologies [23] and their interaction with other constituents. Such information is challenging to acquire using other characterisation techniques with comparable resolution and sample dimensions.

4. Conclusion

In this work, X-ray absorption spectroscopy (XAS) spectra for several common phases identified near the β -SiC_{nw} - AZ91 interface were collected using synchrotron STXM at the energy range near Mg and/or Al K-edge for the first time. To prepare the sample for STXM analysis, analytical SEM and TEM were first used to identify the phases of interest. The common FIB lift-out procedure was then followed to obtain the lamellae for the STXM scans. Comparisons of the NEXAFS spectra obtained for α -Mg and MgO with the spectra reported from the literature, confirmed the validity of the sample preparation and data reduction approaches. This observation increased our confidence for the accuracy of XAS spectra for other phases captured in this study.

The results of this study provided a basis for using STXM as a technique to probe the sub-micron scale features near reinforcements-matrix interface β -SiC reinforced AZ91 matrix, especially the phases with polymorphs of different crystal structures and element oxidation states. The ternary carbides [18] highlighted in this work, along with the AlMn intermetallic phases studied previously [39], play an important role in the development of these alloy nanocomposites. In future work, efforts will focus on expanding the XAS spectra databases for other important interfacial phases such as AlMn intermetallics [39] and various carbides [18], at different element edges (e.g. Si K-edge and Mn L-edge).



(caption on next page)

Fig. 3. (a) SEM-secondary electron (SEM-SE) image of the sample used for capturing reference XAS spectrum for T2-Al₂MgC₂ phase. The inset is the spectrum collected by EDX points analysis. (b) SEM-SE image of the cross-section before lifting out during FIB preparation. The scalebar in this image is 2 μm. (c) EBSD phase mapping of the T2-Al₂MgC₂ used for capturing reference spectrum, in which the orange colour indicates T2-Al₂MgC₂ phase, the green colour indicates β-SiC_{nw} and white colour indicates α-Mg phase. The black colour indicates non-indexed pixels. The scalebar in this image is 500 nm. The region for this EBSD was labelled with white box in (a). (d) Atomic resolution STEM image of T2-Al₂MgC₂ phase captured at [1100] zone axis. The lattice of T2-Al₂MgC₂ was superimposed on the STEM image to indicate the positions of atoms. (e) The low-magnification STEM image of the T2-Al₂MgC₂ phase. (f) The indexed electron diffraction pattern captured at the location labelled in circle in (e). (g) STXM image captured near Mg K-edge at 1315 eV. (h) STXM image captured near Al K-edge at 1587 eV. The regions outlined by yellow dotted lines in image (g) and (h) are the positions used for capturing XAS spectra. (i) The XAS spectrum for T2-Al₂MgC₂ near Mg K-edge. (j) The XAS spectrum for T2-Al₂MgC₂ near Al K-edge.



Fig. 4. (a) SEM-secondary electron (SEM-SE) image of the sample used for capturing reference XAS spectrum for Mg2Si phase (outlined by light blue colour). The inset is the spectrum collected from EDX points analysis. (b) SEM-SE image of the cross-section before lifting out during FIB preparation. (c) STXM image captured near Mg K-edge at 1315 eV. The regions outlined by light blue dotted lines in the image is the position used for capturing XAS spectrum. The scalebars in images (a), (b), and (c) are 2 μ m. (d) The XAS spectrum for Mg₂Si phase near Mg K-edge.



Fig. 5. (a) SEM-secondary electron (SEM-SE) image of the sample used for capturing reference XAS spectrum for MgO. The inset is the spectrum collected from EDX point analysis. (b) SEM-SE image of the cross-section before lifting out during FIB preparation. (c) STXM image captured near Mg K-edge at 1315 eV. The region outlined by purple dotted line in (c) is used for generating XAS spectrum. (d) The XAS spectrum for MgO phase near Mg K-edge captured in this study (Purple line) replotted from W. Klysubun et. al. [30] (Black line).

Additionally, simulations based on density functional theory will be considered in the future works to further improve the accuracy of the captured spectra and gain a better understanding of features in XAS spectra, especially NEXAFS [24]. Having access to these spectral data



Fig. 6. XAS spectra of all the phases captured in this study at energy range (a) near Mg K-edge, and (b) near Al K-edge. The spectra of the phases were colour-coded based on the legend shown on the right hand-side.

Table 2

The near edge X-ray absorption fine structure (NEXAFS) features at Mg K-edge obtained from the XAS spectrum collected in this study.

| Phase | Feature positions | Feature description | Energy shift related to Edge onset |
|-------------------------------------|-------------------|------------------------|---------------------------------------|
| α-Mg (This study) | 1307.0 | Edge onset | 0.0 |
| | 1313.0 | Peak | 6.0 |
| | 1319.0 | Peak | 12.0 |
| α-Mg (from Richardson | 1310.0 | Edge onset | 0.0 |
| et al. [29]) | 1316.3 | Peak | 6.3 |
| | 1321.8 | Peak | 11.8 |
| β-phase | 1308.0 | Edge onset | 0.0 |
| | 1315.0 | Peak | 7.0 |
| | 1321.0 | Peak | 13.0 |
| Mg ₂ Si | 1307.0 | Edge onset | 0.0 |
| | 1309.0 | Peak | 2.0 |
| | 1314.0 | Peak | 7.0 |
| | 1319.0 | Peak | 12.0 |
| | 1320.0 | Peak | 13.0 |
| MgO (This study) | 1310.0 | Edge onset | 0.0 |
| | 1312.0 | Peak | 2.0 |
| | 1317.0 | peak | 7.0 |
| | 1320.0 | Peak | 10.0 |
| MgO (from Wantana | 1310.0 | Edge onset | 0.0 |
| et al., 2017 [30]) | 1311.6 | Peak | 1.6 |
| | 1314.1 | Peak | 4.1 |
| | 1317.2 | Peak | 7.2 |
| | 1319.7 | Peak | 9.7 |
| T2-Al ₂ MgC ₂ | 1307.0 | Edge onset | 0.0 |
| | 1314.0 | Peak | 7.0 |
| | 1317.0 | Peak | 10.0 |

will enable us and wider research community to identify and quantify the presence of specific phase polymorphs, employing methods such as linear combination of XAS spectra.

Table 3

The near edge X-ray absorption fine structure (NEXAFS) features at Al K-edge obtained from the XAS spectrum collected in this study.

| Phase | Feature positions | Feature description | Energy shift related to Edge onset |
|-------------------------------------|-------------------|---------------------|------------------------------------|
| β-phase | 1565.0 | Edge onset | 0.0 |
| | 1566.0 | Peak | 1.0 |
| | 1570.0 | Peak | 5.0 |
| | 1581.0 | Peak | 16.0 |
| T2-Al ₂ MgC ₂ | 1565.0 | Edge onset | 0.0 |
| | 1568.0 | Peak | 3.0 |
| | 1573.0 | Peak | 8.0 |
| | 1575.0 | Peak | 10.0 |
| | 1580.0 | Peak | 15.0 |
| | 1587.0 | Peak | 22.0 |
| | 1589.0 | Peak | 26.0 |
| | 1594.0 | Peak | 29.0 |



Fig. 7. STXM images of the lamella sample used for composition analysis captured at (a) 1313 eV and (b) 1588 eV, respectively. In these two images, the location of SiCnw was labelled by green dotted lines. The region of interest (ROI) 1–3 used for XAS spectrum extraction were presented in (c-e). (f) The XAS spectra of ROI 1–3 near Mg K-edge. (g) The XAS spectra of ROI 1–3 near Al K-edge. The composition analysis for these spectra can be found in Fig. S1.

CRediT authorship contribution statement

Milo S.P. Shaffer: Writing – review & editing, Supervision. Benjamin Watts: Writing – review & editing, Methodology, Investigation. Yuting Dai: Methodology, Investigation. Christian Kübel: Writing – review & editing, Supervision. Qianqian Li: Writing – review & editing, Supervision, Methodology, Investigation, Funding acquisition. Zhuocheng Xu: Writing – original draft, Validation, Methodology, Investigation, Formal analysis, Data curation. Xinyi Hao: Methodology, Investigation.

Declaration of Competing Interest

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

Data availability

Data will be made available on request.

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Appendix A. Supporting information

Supplementary data associated with this article can be found in the online version at doi:10.1016/j.elspec.2024.147477.

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